TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (L<sup>2</sup>-π-MOSV)

# 2SK2376

Chopper Regulator, DC–DC Converter and Motor Drive Applications

- 4-V gate drive
- Low drain-source ON resistance  $: RDS (ON) = 13 m\Omega (typ.)$
- High forward transfer admittance  $: |Y_{fs}| = 40 \text{ S (typ.)}$
- Low leakage current  $: IDSS = 100 \mu A (max) (VDS = 60 V)$
- Enhancement mode  $: V_{th} = 0.8 \sim 2.0 \text{ V} (V_{DS} = 10 \text{ V}, \text{ I}_{D} = 1 \text{ mA})$

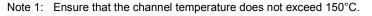
Characteri	stics	Symbol	Rating	Unit
Drain-source voltage		V <sub>DSS</sub>	60	V
Drain-gate voltage (R <sub>GS</sub> = 20 kΩ)		V <sub>DGR</sub>	60	V
Gate-source voltage		V <sub>GSS</sub>	±20	V
Drain current	DC (Note 1)	۱ <sub>D</sub>	45	А
Diamounent	Pulse (Note 1)	I <sub>DP</sub>	180	A
Drain power dissipatio	n (Tc = 25°C)	PD	100	W
Single pulse avalanch	e energy (Note 2)	E <sub>AS</sub>	701	mJ
Avalanche current		I <sub>AR</sub>	45	A
Repetitive avalanche e	energy (Note 3)	E <sub>AR</sub>	10	mJ
Channel temperature		T <sub>ch</sub>	150	°C
Storage temperature range		T <sub>stg</sub>	-55~150	°C

### Absolute Maximum Ratings (Ta = 25°C)

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

### **Thermal Characteristics**

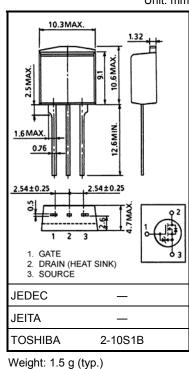
Characteristics	Symbol	Max	Unit	
Thermal resistance, channel to case	R <sub>th (ch-c)</sub>	1.25	°C / W	
Thermal resistance, channel to ambient	R <sub>th (ch-a)</sub>	83.3	°C / W	

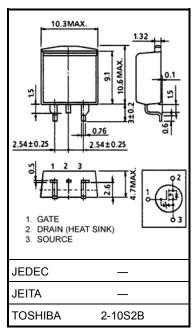


Note 2:  $V_{DD}$  = 25 V,  $T_{ch}$  = 25°C (initial), L = 471 µH,  $R_G$  = 25  $\Omega$ ,  $I_{AR}$  = 45 A

Note 3: Repetitive rating: pulse width limited by maximum channel temperature

This transistor is an electrostatic-sensitive device. Please handle with caution.





Weight: 1.5 g (typ.)

Unit: mm

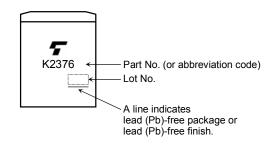
# Electrical Characteristics (Ta = 25°C)

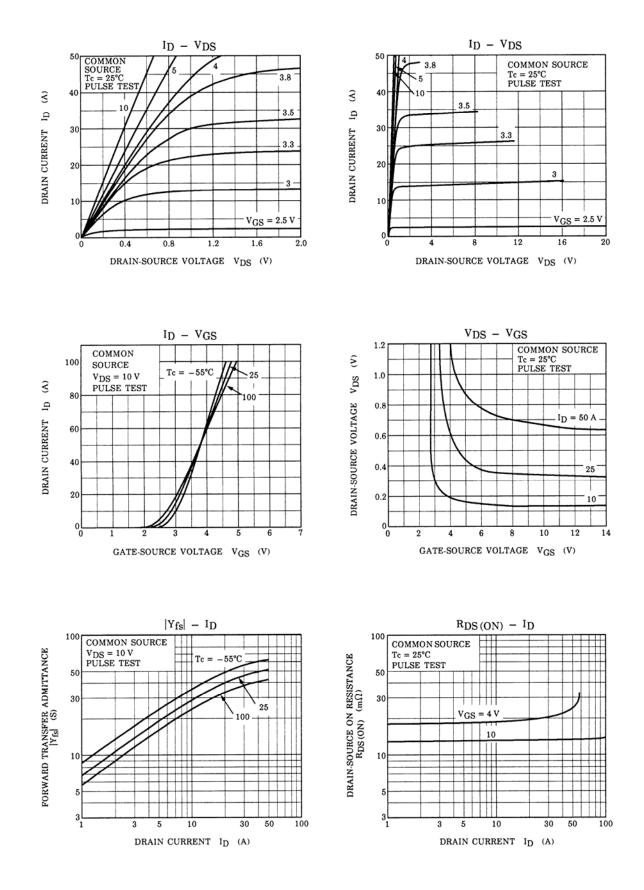
Charae	cteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cu	urrent	I <sub>GSS</sub>	V <sub>GS</sub> = ±16 V, V <sub>DS</sub> = 0 V	_	_	±10	μA
Drain cut-off cu	-off current $I_{DSS}$ $V_{DS}$ = 60 V, $V_{GS}$ = 0 V		V <sub>DS</sub> = 60 V, V <sub>GS</sub> = 0 V		_	100	μA
Drain-source bi	reakdown voltage	V (BR) DSS	I <sub>D</sub> = 10 mA, V <sub>GS</sub> = 0 V	60	_		V
Gate threshold	voltage	V <sub>th</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 1 mA	0.8	_	2.0	V
Drain-source ON resistance		R <sub>DS (ON)</sub>	V <sub>GS</sub> = 4 V, I <sub>D</sub> = 25 A	_	19	25	
			V <sub>GS</sub> = 10 V, I <sub>D</sub> = 25 A		13	17	mΩ
Forward transfe	r admittance	Y <sub>fs</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 25 A	28	40		S
Input capacitand	ce	C <sub>iss</sub>			3350		pF
Reverse transfer capacitance		C <sub>rss</sub>	V <sub>DS</sub> = 10 V, V <sub>GS</sub> = 0 V, f = 1 MHz		550		
Output capacitance		Coss			1600		
Switching time	Rise time	tr	$v_{GS} \stackrel{10V}{}_{0V} \prod_{OV\\ CS\\ V \\ CS\\ V \\ T $		25	_	
	Turn-on time	t <sub>on</sub>			55	_	- ns
	Fall time	t <sub>f</sub>			60	_	
	Turn-off time	t <sub>off</sub>	$VDD \stackrel{=}{\Rightarrow} 30V$ Duty $\leq 1\%$ , t <sub>w</sub> =10 $\mu$ s		180	_	
Total gate charge (Gate-source plus gate-drain)		Qg	V <sub>DD</sub> ≈ 48 V, V <sub>GS</sub> = 10 V, I <sub>D</sub> = 45 A		110	_	nC
Gate-source charge		Q <sub>gs</sub>			70	_	
Gate-drain ("miller") charge		Q <sub>gd</sub>			40	—	

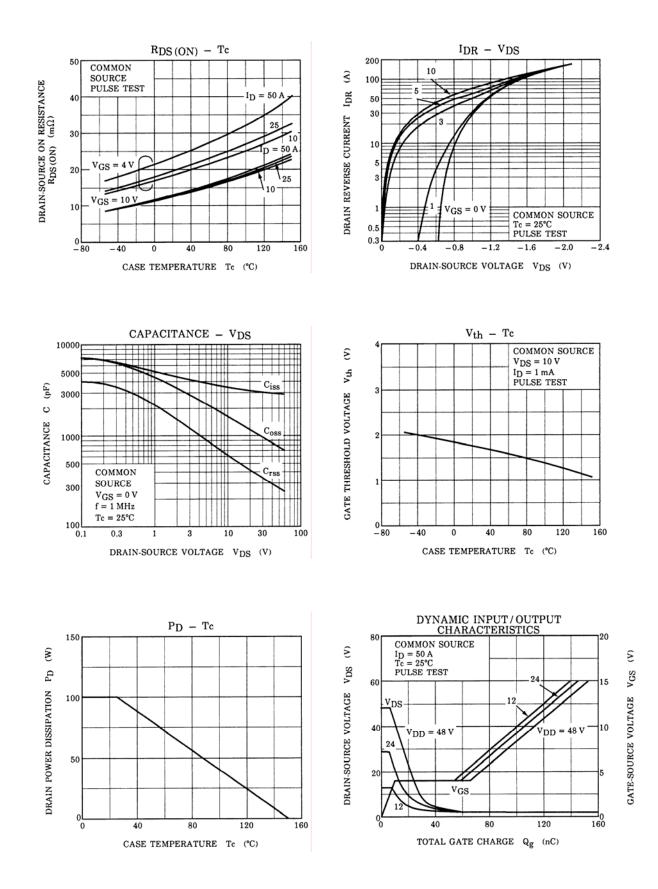
### Source–Drain Ratings and Characteristics (Ta = 25°C)

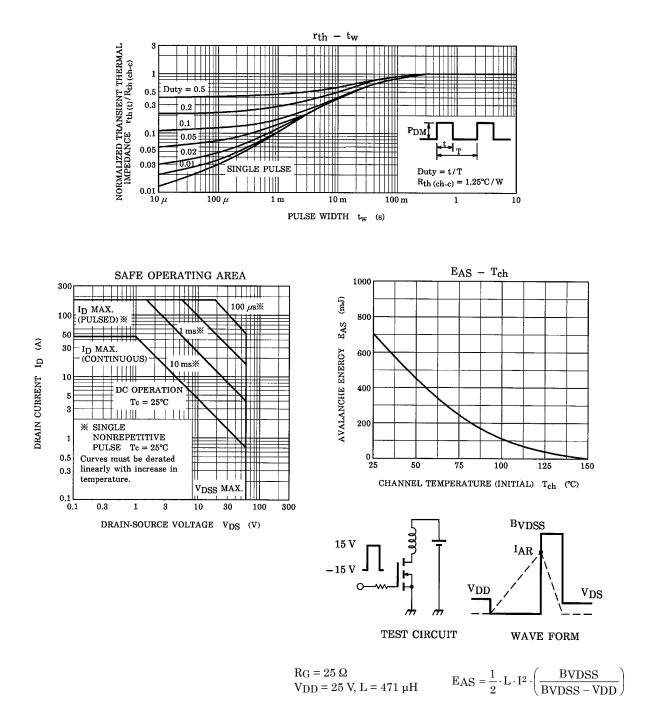
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I <sub>DR</sub>	—	_	_	45	А
Pulse drain reverse current (Note 1)	I <sub>DRP</sub>	—	_	_	180	A
Forward voltage (diode)	V <sub>DSF</sub>	I <sub>DR</sub> = 45 A, V <sub>GS</sub> = 0 V			-1.7	V
Reverse recovery time	t <sub>rr</sub>	I <sub>DR</sub> = 45 A, V <sub>GS</sub> = 0 V dI <sub>DR</sub> / dt = 50 A / μs		120	1	ns
Reverse recovery charge	Q <sub>rr</sub>		_	0.2	_	μC

## Marking









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